## I. <u>AMENDMENTS TO THE CLAIMS</u>:

Please cancel claims 2, 9 and 10 without prejudice. Kindly amend claims 1, 3, 5, 14, 25 and 26 as follows.

The following claims will replace all prior versions of claims in the present application.

## **Listing of Claims:**

1. (Currently Amended) A method of inspecting a target by tera-hertz wave spectroscopic measurement, comprising:

a spectroscopic measurement step of pre-measuring a first spectrum matrix [S] of tera-hertz wave absorbencies of a target component for a plurality of frequencies ranging from about 1 THz to 3 THz;

an object spectroscopic step of irradiating an object with tera-hertz waves of the plurality of frequencies to measure absorbencies of the object; and

determining presence or absence of the target component in the object on the basis of the first spectrum matrix [S] of tera-hertz wave absorbencies and a second spectrum matrix [I] of tera-hertz wave absorbencies of the object; and

a density calculation step of calculating a target density [P] on the basis of the first spectrum matrix [S] of tera-hertz wave absorbencies and the second spectrum matrix [I] of tera-hertz wave absorbencies of the object.

## 2. (Cancelled)

3. (Currently Amended) A method of inspecting a target according to <u>claim 1elaim</u> 2, wherein the target spectroscopic step comprises a step of two-dimensionally scanning the object with the tera-hertz waves to measure the two-dimensional distribution matrix [I] of

absorbency of penetration light,

and the density calculation step comprises a step of calculating the two-dimensional distribution matrix [P] of the target density, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M, wherein

when N is equal to M, the two-dimensional distribution matrix [P] of the target density is calculated by  $[P] = [S]^{-1}[I]$ ,

and when N is larger than M, the two-dimensional distribution matrix [P] of the target density is calculated by [I] = [S][P], using a least square method.

- 4. (Previously Presented) A method of inspecting a target according to claim 3, further comprising a step of two-dimensionally displaying the two-dimensional distribution matrix [P] of the target density.
- 5. (Currently Amended) A method of inspecting a target according to <u>claim 1elaim</u> 2, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M, wherein

when N is equal to M, the two-dimensional distribution matrix [P] of the target density is calculated by  $[P] = [S]^{-1}[I]$ ,

and when N is larger than M, the two-dimensional distribution matrix [P] of the target density is calculated by [I] = [S][P], using a least square method.

- 6. (Previously Presented) An apparatus for inspecting a target using tera-hertz wave spectroscopic measurement, comprising:
- a tera-hertz wave generation device that generates tera-hertz waves of a plurality of wavelengths;
  - a two-dimensional scan device that scans an object with the tera-hertz waves of the

Patent Application Serial No. 10/550,303 Attorney Docket No. **ASAIN0167** 

plurality of wavelengths;

a spectroscopic measurement device that measures a two-dimensional distribution matrix [I] of light absorbency of the object; and

a target density calculation device that calculates a two-dimensional distribution matrix [P] of a target density on the basis of a pre-measured spectrum matrix [S] of light absorbency of a target and the two-dimensional distribution matrix [I] of light absorbency.

- 7. (Previously Presented) An apparatus for inspecting a target by tera-hertz wave spectroscopic measurement, according to claim 6, further comprising an image display device that two-dimensionally displays an image of the two-dimensional distribution matrix [P] of the target density.
- 8. (Previously Presented) A method of inspecting a target according to claim 3, further comprising a step of two-dimensionally displaying the two-dimensional distribution matrix [P] of the target density.
  - 9. (Cancelled)
  - 10. (Cancelled)
- 11. (Previously Presented) A method of inspecting a target according to claim 1, wherein determination of the presence or absence of the target component is performed without opening the object.
- 12. (Previously Presented) A method of inspecting a target by tera-hertz wave spectroscopic measurement, comprising the steps of:

pre-measuring a first spectrum matrix [S] of tera-hertz wave absorbencies of a target component for a plurality of frequencies ranging from about 1 THz to 3 THz;

irradiating an object with tera-hertz waves of the plurality of frequencies to measure absorbencies of the object; and

determining presence or absence of the target component in the object on the basis of the first spectrum matrix [S] of tera-hertz wave absorbencies and a second spectrum matrix [I] of tera-hertz wave absorbencies of the object.

13. (Previously Presented) A method of inspecting a target according to claim 12, further comprising the steps of:

calculating a target density on the basis of the first spectrum matrix [S] of tera-hertz wave absorbencies and the second spectrum matrix [I] of tera-hertz wave absorbencies of the object, wherein the target density is a two-dimensional distribution matrix [P], and premeasuring the first spectrum matrix [S] comprises two-dimensionally scanning the object with the tera-hertz waves to measure a two-dimensional distribution matrix [I] of absorbency of penetration light; and

two-dimensionally displaying the two-dimensional distribution matrix [P] of the target density.

14. (Currently Amended) A method of inspecting a target according to <a href="mailto:claim12elaim13">claim12elaim13</a>, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M, wherein

when N is equal to M, the two-dimensional distribution matrix [P] of the target density is calculated by  $[P] = [S]^{-1}[I]$ ,

and

when N is larger than M, the two-dimensional distribution matrix [P] of the target density is calculated by [I] = [S][P], using a least square method.

- 15. (Previously Presented) A method of inspecting a target according to claim 12, wherein determination of the presence or absence of the target component is performed without opening the object.
- 16. (Previously Presented) An apparatus for inspecting a target by tera-hertz wave spectroscopic measurement according to claim 6, wherein tera-hertz waves of N number of different wavelengths are used for M number of targets, N being equal to or larger than M, wherein the target density calculation device calculates the two-dimensional distribution matrix [P] as follows:

when N is equal to M, the two-dimensional distribution matrix [P] of the target density is calculated by  $[P] = [S]^{-1}[I]$ , and

when N is larger than M, the two-dimensional distribution matrix [P] of the target density is calculated by [I] = [S][P], using a least square method.

- 17. (Previously Presented) An apparatus for inspecting a target by tera-hertz wave spectroscopic measurement according to claim 6, wherein the target density calculation device determines a presence or absence of a target component in the object using the calculated two-dimensional distribution matrix [P] and without opening the object.
- 18. (Previously Presented) A method of inspecting a target according to claim 1, wherein the object is an article that is capable of containing the target component.

Patent Application Serial No. 10/550,303 Attorney Docket No. **ASAIN0167** 

- 19. (Previously Presented) A method of inspecting a target according to claim 18, wherein the article is selected from the group consisting of an envelope, a parcel and a container.
- 20. (Previously Presented) A method of inspecting a target according to claim 18, wherein the target component is selected from the group consisting of a drug and bio-powder.
- 21. (Previously Presented) A method of inspecting a target according to claim 12, wherein the object is an article that is capable of containing the target component.
- 22. (Previously Presented) A method of inspecting a target according to claim 21, wherein the article is selected from the group consisting of an envelope, a parcel and a container.
- 23. (Previously Presented) A method of inspecting a target according to claim 21, wherein the target component is selected from the group consisting of a drug and bio-powder.
- 24. (Previously Presented) An apparatus for inspecting a target by tera-hertz wave spectroscopic measurement according to claim 17, wherein the object is an article that is capable of containing the target component.
- 25. (Currently Amended) <u>An apparatus for A method of inspecting a target by terahertz wave spectroscopic measurement according to claim 24, wherein the article is selected from the group consisting of an envelope, a parcel and a container.</u>

26. (Currently Amended) <u>An apparatus for A method of inspecting a target by tera-</u>
hertz wave spectroscopic measurement according to claim 24, wherein the target component is selected from the group consisting of a drug and bio-powder.